


<b>Search Notes</b>  	<b>Application/Control No.</b>  10563274	<b>Applicant(s)/Patent Under Reexamination</b>  SHIONO ET AL.
	<b>Examiner</b>  Kim-Kwok CHU	<b>Art Unit</b>  2627

SEARCHED			
Class	Subclass	Date	Examiner
369	44.23	6/6/2011	kc
369	13.26	6/6/2011	kc
369	44.12	6/6/2011	kc
369	44.37	6/6/2011	kc
369	44.26	6/6/2011	kc
369	44.34	6/6/2011	kc
369	112.01	6/6/2011	kc
369	275.4	6/6/2011	kc
369	275.3	6/6/2011	kc
369	112.29	6/6/2011	kc
369	44.18	6/6/2011	kc
369	44.22	6/6/2011	kc
369	44.37	6/6/2011	kc
369	97	6/6/2011	kc
369	13.35	6/6/2011	kc

SEARCH NOTES		
Search Notes	Date	Examiner
East Search Updated	6/6/2011	kc

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
369	44.23	6/6/2011	kc
369	112.01	6/6/2011	kc
369	44.37	6/6/2011	kc

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